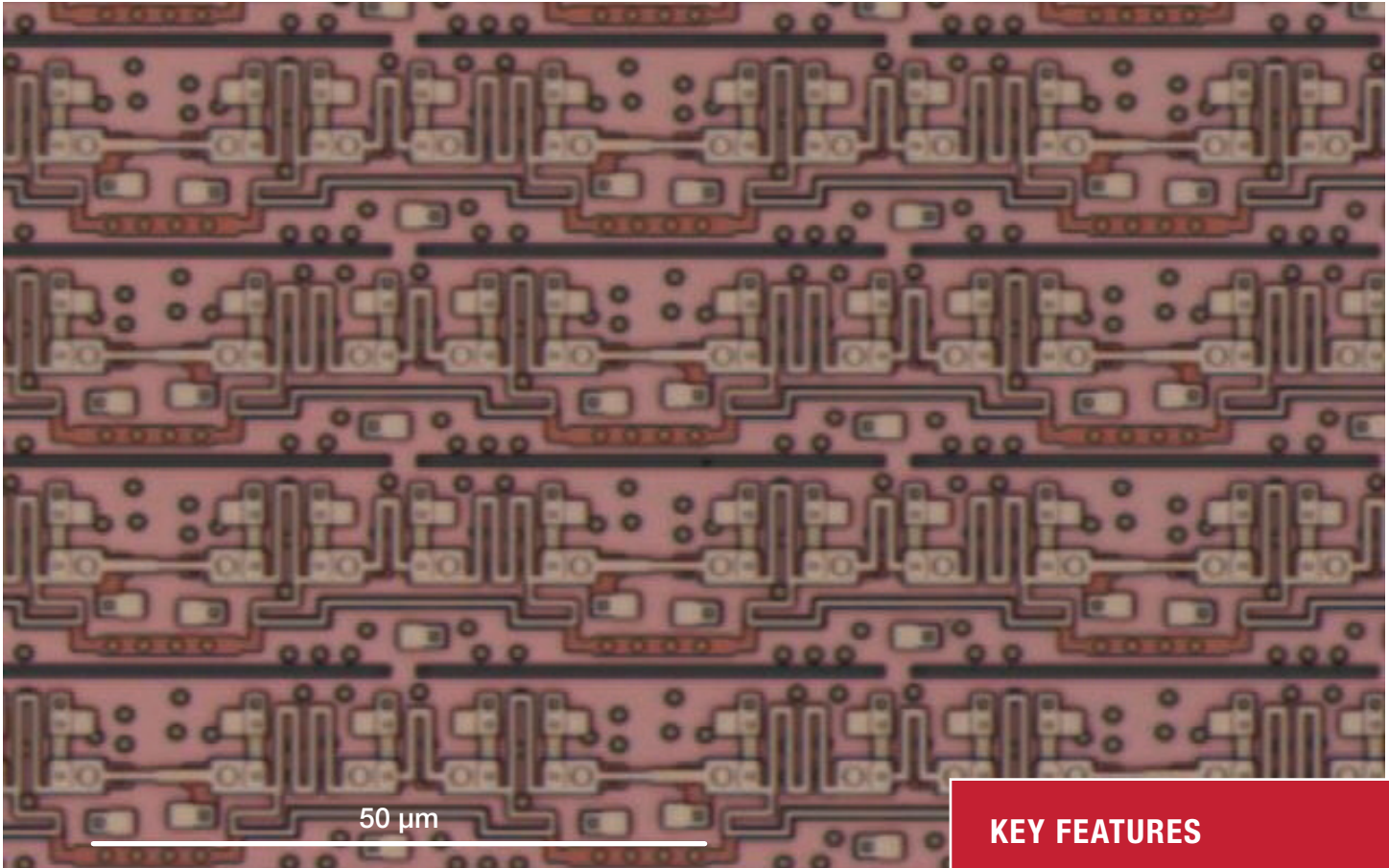


# Superconducting Integrated Circuits



Photomicrograph of superconducting single-flux-quantum (SFQ) shift-register integrated circuit fabricated at Lincoln Laboratory.

MIT Lincoln Laboratory has developed the world's most advanced single-flux-quantum (SFQ) integrated circuit process. This research foundry capability enables prototyping of advanced SFQ circuits along with flip-chip packaging on superconducting multi-chip modules.

## KEY FEATURES

- Superconductive SFQ circuits with fast switching speed and low switching energy unmatched by any other demonstrated integrated circuit technology
- SFQ circuits demonstrated with up to 809,000 Josephson junctions, a world record
- Cryogenic operation

## Lincoln Laboratory Processes

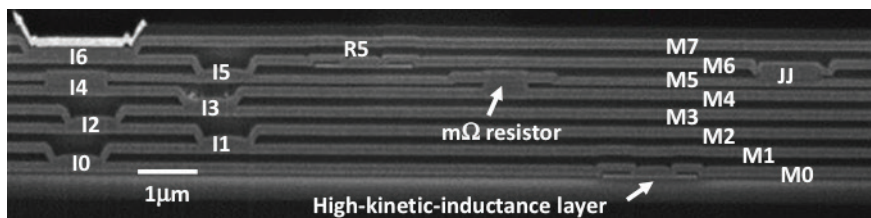
Multiple SFQ research foundry fabrication process nodes are either offered or under development as outlined in the MIT Lincoln Laboratory SFQ Technology Roadmap. The table below outlines key features and dimensions offered for each process node. By adding more wiring layers, incorporating stud vias, and reducing

minimum linewidths, higher circuit densities can be achieved. New process features are first made available to circuit design teams while the process is matured. A new high- $J_C$  process, SFQ5hs, is available for 2017. Future nodes, such as SFQ7ee, will feature additional wiring layers and reduced minimum feature sizes.

| Fabrication Process Attribute |                 | Units             | Process Node      |                     |                     |                   |                     |               |
|-------------------------------|-----------------|-------------------|-------------------|---------------------|---------------------|-------------------|---------------------|---------------|
|                               |                 |                   | SFQ3ee            | SFQ4ee              | SFQ5ee              | SFQ6ee            | SFQ5hs              | SFQ7ee        |
| Critical current density      |                 | MA/m <sup>2</sup> | 100               | 100                 | 100                 | 100               | 200                 | 100           |
| JJ diameter (surround)        |                 | nm                | 700 (500)         | 700 (500)           | 700 (500)           | 700 (300)         | 700 (500)           | 500 (200)     |
| Nb metal layers               |                 | –                 | 4                 | 8                   | 8                   | 9                 | 8                   | 10            |
| Line width (space)            | Critical layers | nm                | 500 (1000)        | 500 (700)           | 350 (500)           | 350 (400)         | 350 (500)           | 250 (300)     |
|                               | Other layers    | nm                |                   |                     | 500 (700)           | 500 (700)         | 500 (700)           | 350 (500)     |
| Metal thickness               |                 | nm                | 200               | 200                 | 200                 | 200               | 200                 | 200           |
| Dielectric thickness          |                 | nm                | 200               | 200                 | 200                 | 200               | 200                 | 200           |
| Resistor width (space)        |                 | nm                | 1000 (2000)       | 500 (700)           | 500 (700)           | 500 (700)         | 500 (700)           | 500 (500)     |
| Shunt resistor value          |                 | Ω/sq              | 2                 | 2                   | 2 or 6              | 2 or 6            | 2 or 6              | 2 or 6        |
| mΩ resistor                   |                 | mΩ                | –                 | –                   | 3–10                | 3–10              | 3–10                | 3–10          |
| High kinetic inductance layer |                 | pH/sq             | –                 | –                   | 8                   | 8                 | 8                   | 8             |
| Via diameter (surround)       |                 | nm                | 700 (500)         | 700 (500)           | 500 (500)           | 500 (500)         | 500 (500)           | 350 (250)     |
| Via type, stacking            |                 | –                 | Etched, staggered | Etched, stacked \2/ | Etched, stacked \2/ | Stud, stacked \2/ | Etched, stacked \2/ | Stud, stacked |
| Early access availability     |                 | –                 |                   | 2014                | 2015                | 2016              | 2017                | 2018          |

Red text indicates changes from the previous process.

## SFQ5ee Process Node



Cross section of an SFQ integrated circuit fabricated in Lincoln Laboratory’s SFQ5ee process node. The eight Nb wiring layers (M0–M7) are visible along with etched vias (I0–I6). The Josephson junction (JJ) is placed between M5 and M6. The resistor layer (R5), the milliohm (mΩ) resistor, and the high-kinetic-inductance layer are also indicated.

The SFQ5ee process provides attractive features:

- 700-nm Josephson junctions
- Eight Nb wiring layers
- 350-nm wiring feature size
- High-kinetic-inductance layer

## Applications

Our SFQ integrated circuits can have application in a variety of fields:

- High-performance digital computing
- Wideband mixed RF/digital processing
- Quantum computing

### TECHNICAL CONTACT

**Leonard Johnson**  
*Quantum Information and Integrated Nanosystems Group*

MIT Lincoln Laboratory,  
 244 Wood Street, Lexington, MA 02421

ljohnson@ll.mit.edu

Approved for public release; distribution unlimited. This material is based upon work supported by the Office of the Director of National Intelligence (ODNI), Intelligence Advanced Research Projects Activity (IARPA) under Air Force Contract no. FA8721-05-C-0002. Any opinions, findings and conclusions, or recommendations expressed in this material are those of the author and do not necessarily reflect the views of the ODNI-IARPA. Delivered to the U.S. government with unlimited rights, as defined in DFARS Part 252.227-7013 or 7014 (Feb 2014). Use of this work other than as specifically authorized by the U.S. government may violate any copyrights that exist in this work.  
 © 2017 Massachusetts Institute of Technology